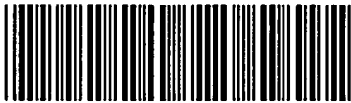


Search Notes

Application/Control No.

10/067,304

Examiner

Ba Huynh

Applicant(s)/Patent under
Reexamination

FUJII ET AL.

Art Unit

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SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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| East: USpat, USpgpub, Epo, Jpo, Derwent, IBM-tdb files search updated | 6/24/2006 | HB |
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